

RELIABILITY PHYSICS

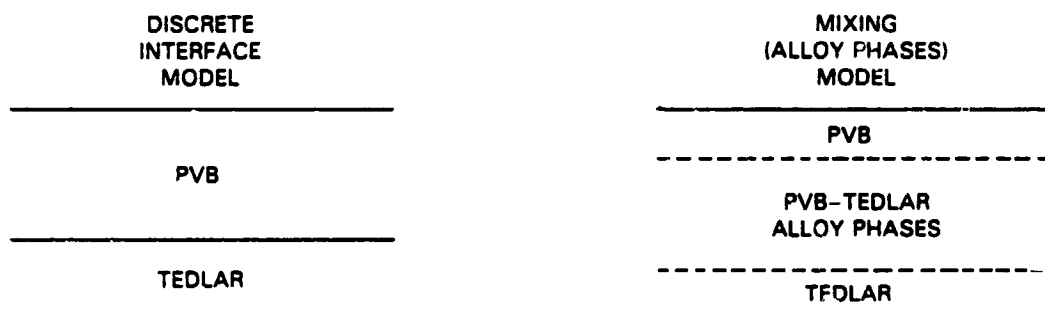
N87-16442

# WATER PERMEATION AND ELECTRICAL PROPERTIES OF POTTANTS, BACKINGS, AND POTTANT/BACKING COMPOSITES

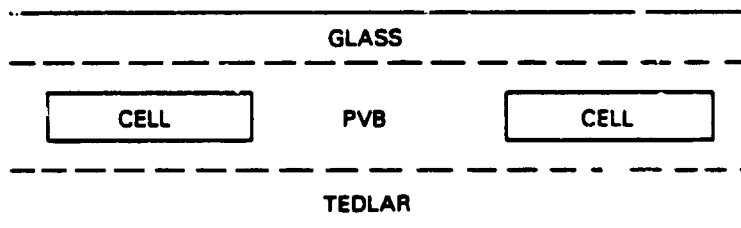
WILKES COLLEGE

J. Orehotsky

Laminates



FOR PATH OF LEAST RESISTANCE IN



## Electrical Properties

- Pottants (PVB, EMA, EVA)
- Backing (Tedlar, Mylar)
- Composites (PVB/T, EMA/T, EVA/T)

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## Object

To Examine Interfacial Effects  
by  
Evaluating

- DC Dielectric Constant (K)
- AC Dielectric Constant (K)
- Leakage Resistance (R)

of

Pottants (PVB, EMA, EVA)

Backing (Tedlar, Mylar)

Composites (PVB/T, EMA/T, EVA/T)

## Theory

### Discrete Interface Model

$$K_{p/b} = \frac{K_p K_b [t_p + t_b]}{K_p t_b + K_b t_p}$$

$$R_{p/b} = \frac{\rho_p t_p + \rho_b t_b}{A}$$

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DC Dielectric Constant by Charge Measurements Before and After Dipole Alignment

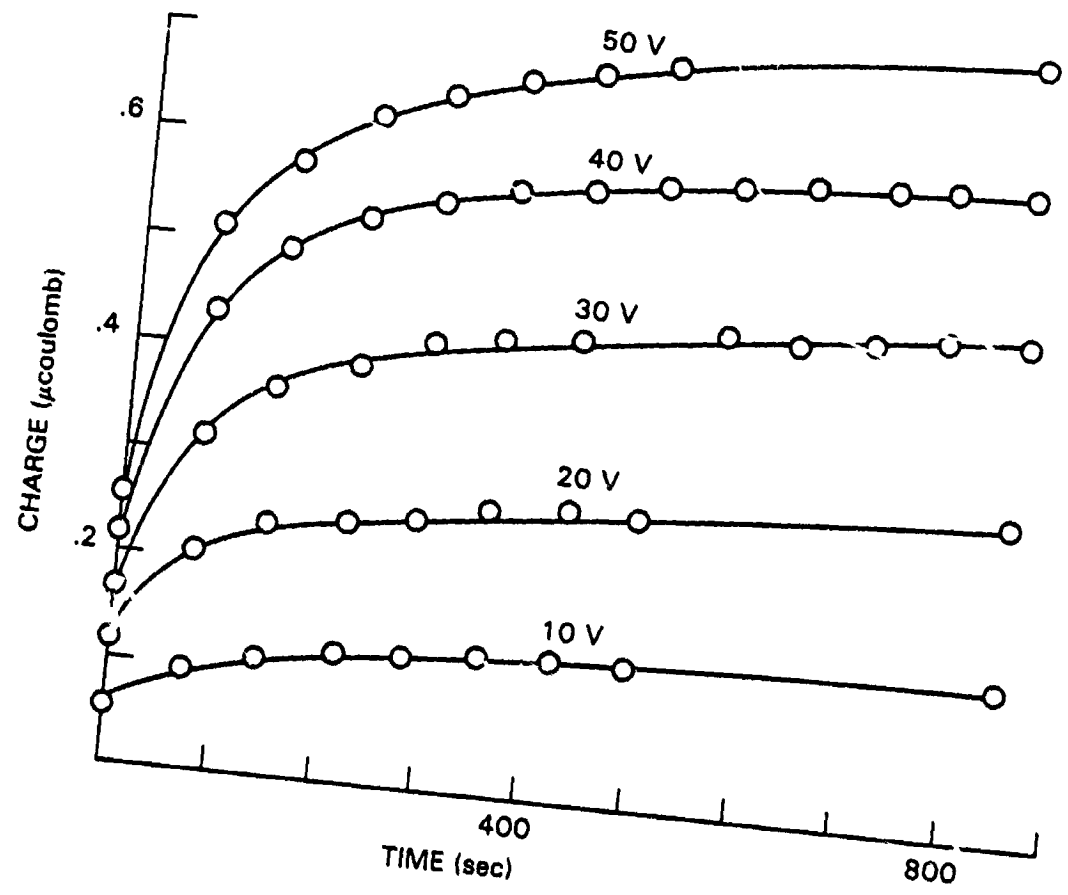
Before:

$$K_i = \frac{[dQ_i/dV_A]t}{\epsilon_0 A}$$

After:

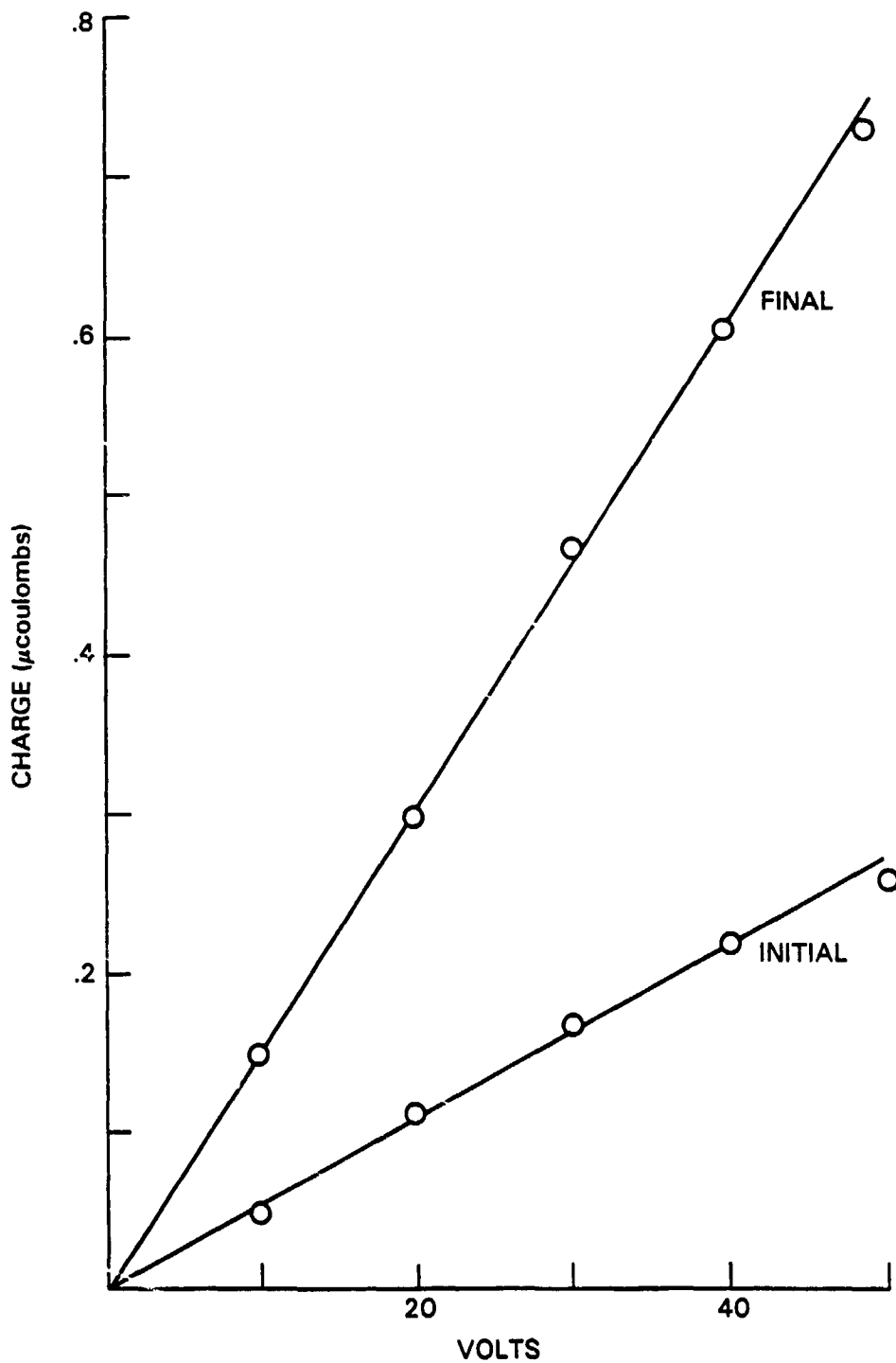
$$K_f = \frac{[dQ_f/dV_A]t}{\epsilon_0 A}$$

TEDLAR



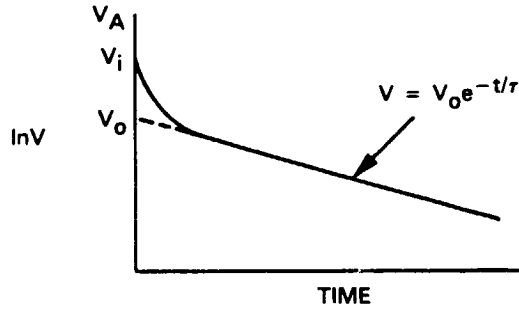
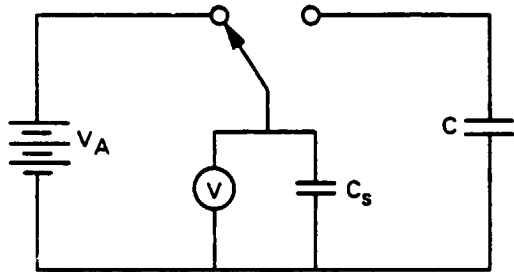
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TEDLAR



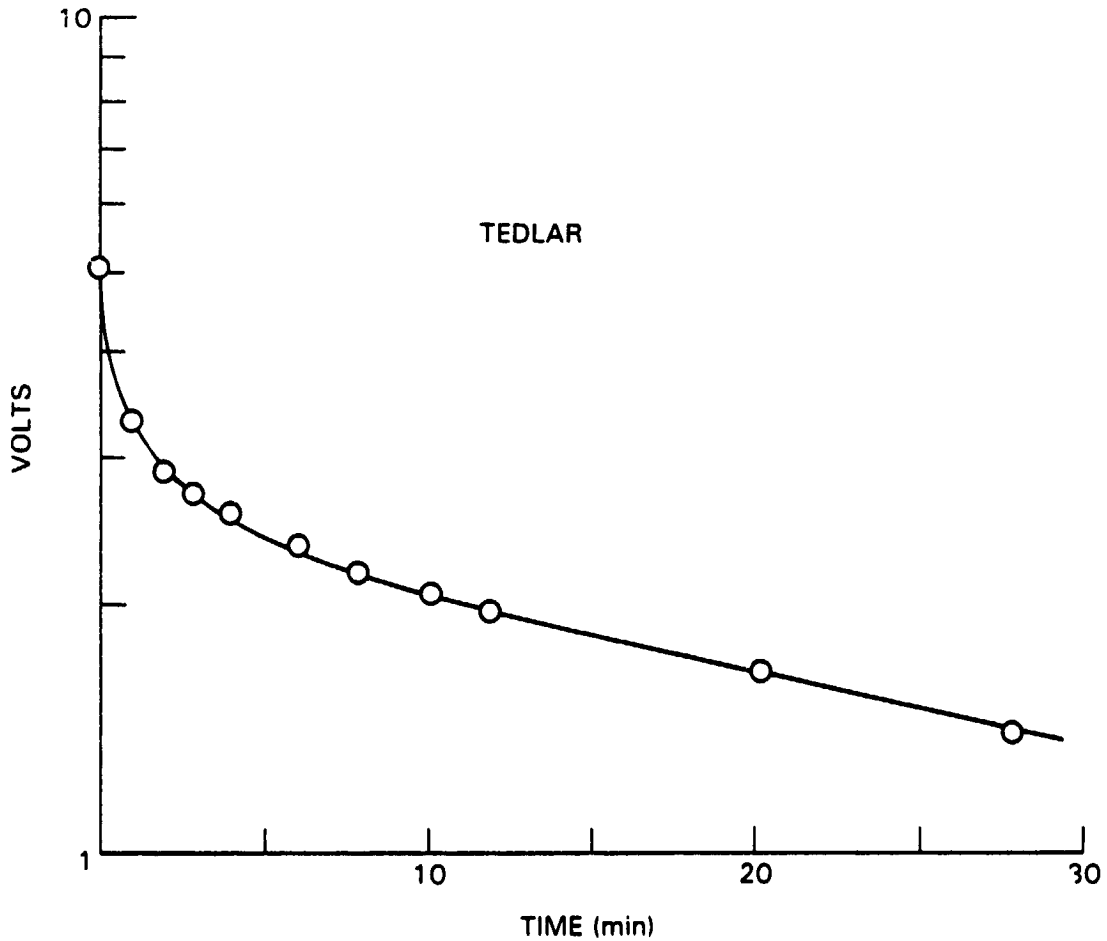
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DC Dielectric Constant by Voltage Measurements Using Charge Transfer from Standard Capacitor ( $C_s$ )

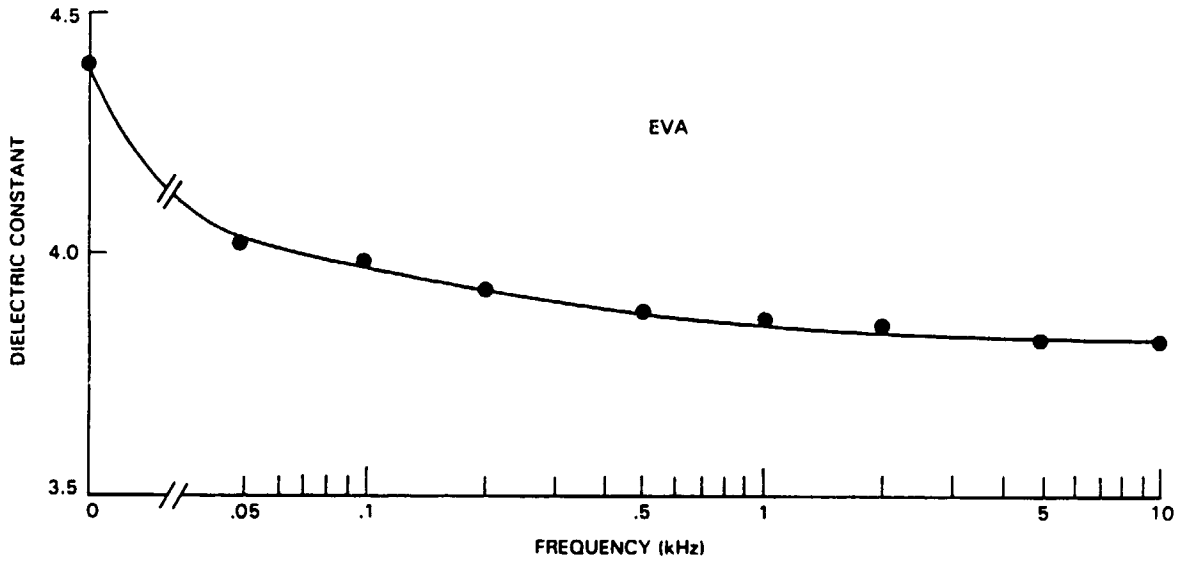


$$K_i = \frac{C_s t}{\epsilon_0 A} \left[ \frac{V_A - V_i}{V_i} \right]$$

$$K_f = \frac{\tau}{\epsilon_0 A} \left[ \frac{\tau}{R} - C_s \right]$$



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## Results

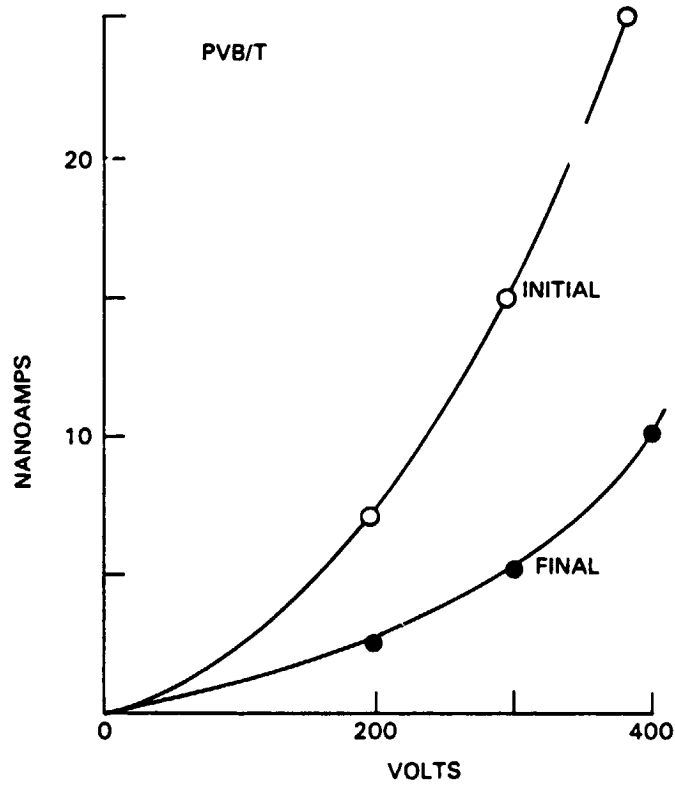
### Dielectric Constant

	DC						AC	
	Before			After			1 kHz	Calc.
	<u>Q</u>	<u>V</u>	<u>Calc.</u>	<u>Q</u>	<u>V</u>	<u>Calc.</u>		
PVB	-	6.0		-	8.0		8.7	
EMA	4.3	4.7		4.3	7.1		3.1	
EVA	5.2	4.3		9.4	10.0		3.9	
Tedlar	4.5	4.3		12.7	12.0		3.7	
Mylar	1.3	1.4		-	-		-	
PV3/T	9.1	8.2	5.7	-	-	8.4	4.8	7.3
EMA/T	4.0	3.2	4.3	-	4.7	4.7	3.1	3.1
EVA/T	4.4	4.7	4.7	-	-	9.9	3.7	3.9

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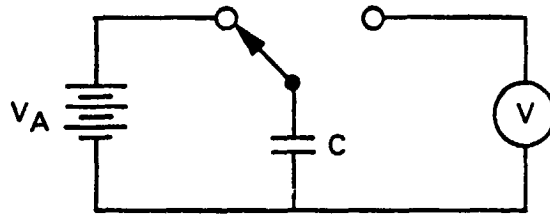
Leakage Resistance by Current-Voltage Measurements and Ohm's Law

$$R = dV_A/JI$$



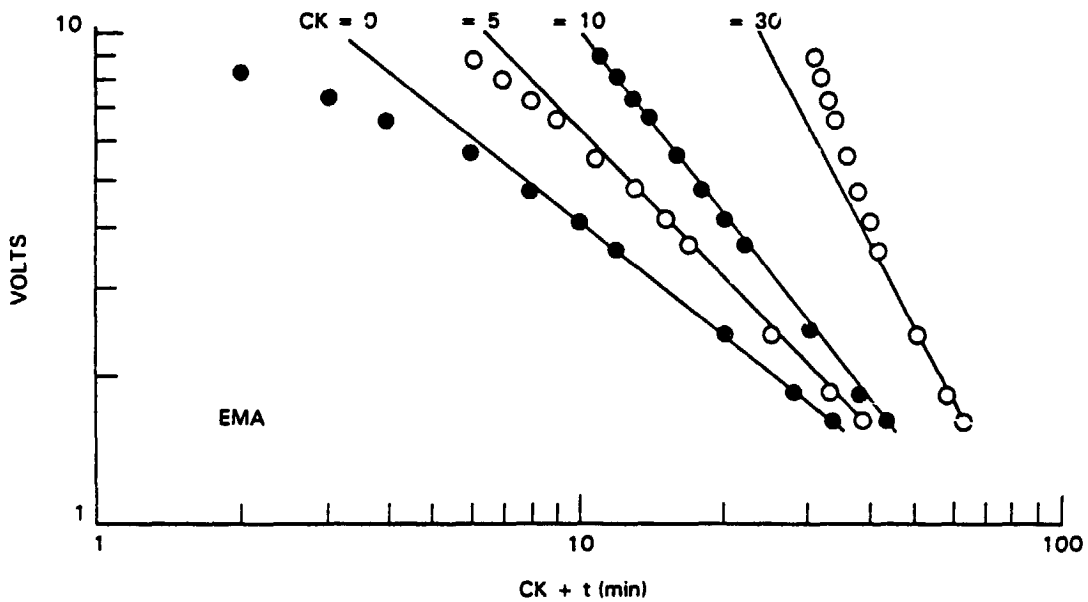
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## Leakage Resistance by Voltage Decay of a Capacitor



THEORY:

$$V = V_0 CK^{K/R}[CK+t]^{-K/R}$$



### Results: Leakage Resistance ( $\Omega$ )

	<u>Ohm's Law</u>	<u>Voltage Decay</u>	<u>Calc.</u>
PVB	1.0(10 <sup>7</sup> )	0.4(10 <sup>7</sup> )	
EMA	1.0(10 <sup>12</sup> )	0.9(10 <sup>12</sup> )	
EVA	0.4(10 <sup>11</sup> )	4.6(10 <sup>11</sup> )	
Tedlar	3.5(10 <sup>11</sup> )	2.0(10 <sup>11</sup> )	
Mylar	—	1.4(10 <sup>13</sup> )	
PVB/T	0.2(10 <sup>12</sup> )	6.8(10 <sup>9</sup> )	3.4(10 <sup>12</sup> )
EMA/T	0.3(10 <sup>13</sup> )	2.3(10 <sup>13</sup> )	0.1(10 <sup>13</sup> )
EVAT	0.3(10 <sup>12</sup> )	0.8(10 <sup>12</sup> )	3.4(10 <sup>12</sup> )



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### Results: Leakage Resistivities ( $\Omega\text{-m}$ )

PVB	$3(10^7)$
EVA	$5(10^{11})$
EMA	$1(10^{13})$
Tedlar	$4(10^{14})$
Mylar	$2(10^{15})$

### Results: Are They Consistent with Discrete Interface Model?

Test	Composite Material		
	<u>EVA/T</u>	<u>EMA/T</u>	<u>PVB/T</u>
DC diel.	Yes	Yes	No
AC diel.	Yes	Yes	No
Resis.	No	Yes	No

### Summary

- EMA/T Obeys Discrete Interface Model
- PVB/T Does Not Obey Discrete Interface Model
- Order of Increasing Leakage is Mylar, Tedlar, EMA, EVA, PVB
- Charged Capacitor-Voltage Decay Kinetics Obey Theoretically Predicted Relationship:

$$V = V_0 CK^{K/R}[CK + t]^{-K/R}$$

## Water Permeation

- Pottants (PVB, EMA, EVA)
- Backing (Tedlar, Mylar)
- Composites (PVB/T, EMA/T, EVA/T)

## Object

Theoretically and Experimentally Evaluate

- Temperature Dependence of  
J (water flux)  
and  
P (water permeability)  
in  
Pottants (p) and Backing (b)
- $P_{p/b}$  of p/b Composite in terms of  
 $P_p$  and  $P_b$

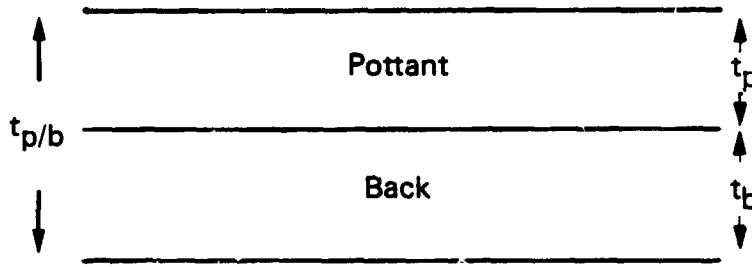
## Theory: Condensation — Self Diffusion — Evaporation Model for Pottants and Backing

- $P_T = P_0 \exp(-Q_p/RT)$   
 $Q_p = 4.6 \text{ Kcal/mole}$  (water self-diffusion  
activation energy)
- $J_T^{6.5} = J_0 \exp(-Q_J/RT)$   
 $Q_J = 4.6 + 9.8 = 14.4 \text{ Kcal/mole}$   
(water self-diffusion + water heat of  
vaporization)  
 $J_0 \sim S$  (water solubility parameter)

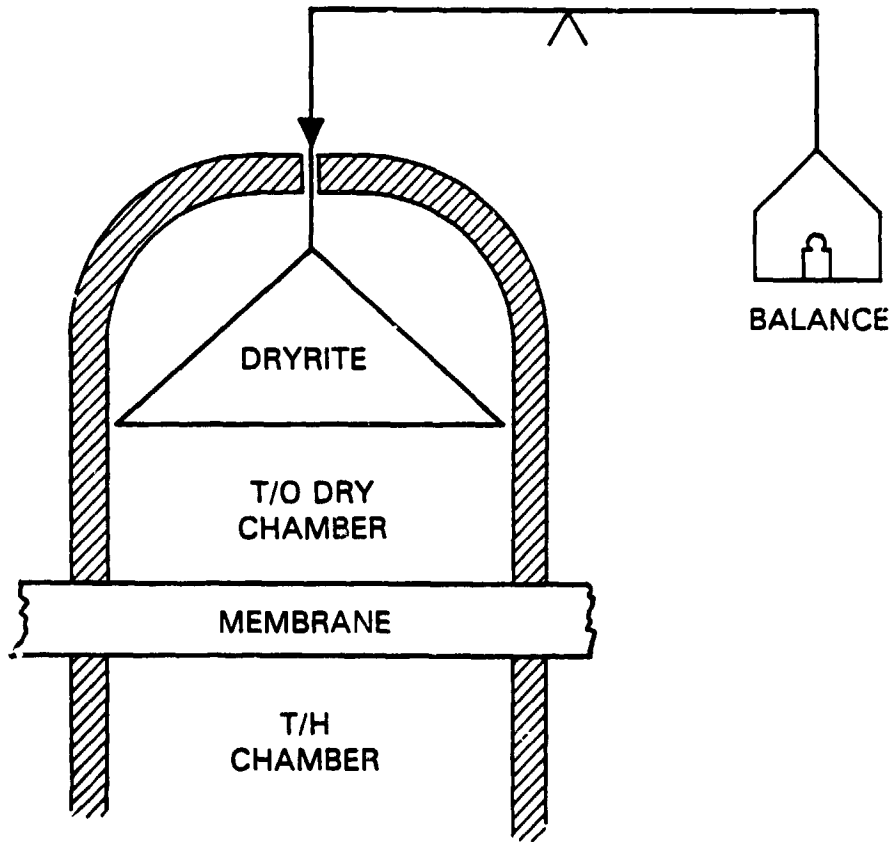
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Theory: Discrete Interface Model for Composites (p/b)

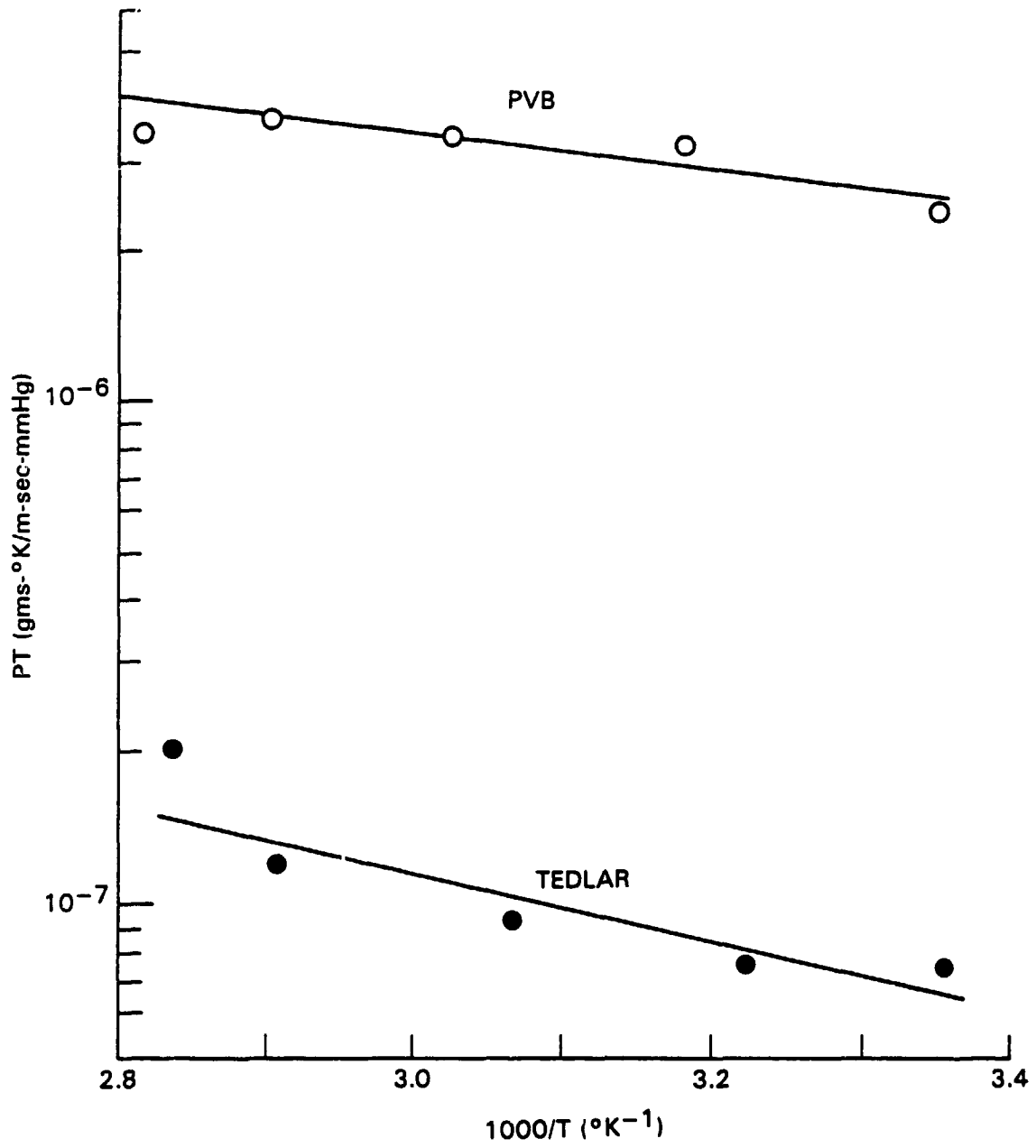
$$P_{p/b} = \frac{t_{p/b} P_p P_b}{P_p t_b + P_b t_p}$$



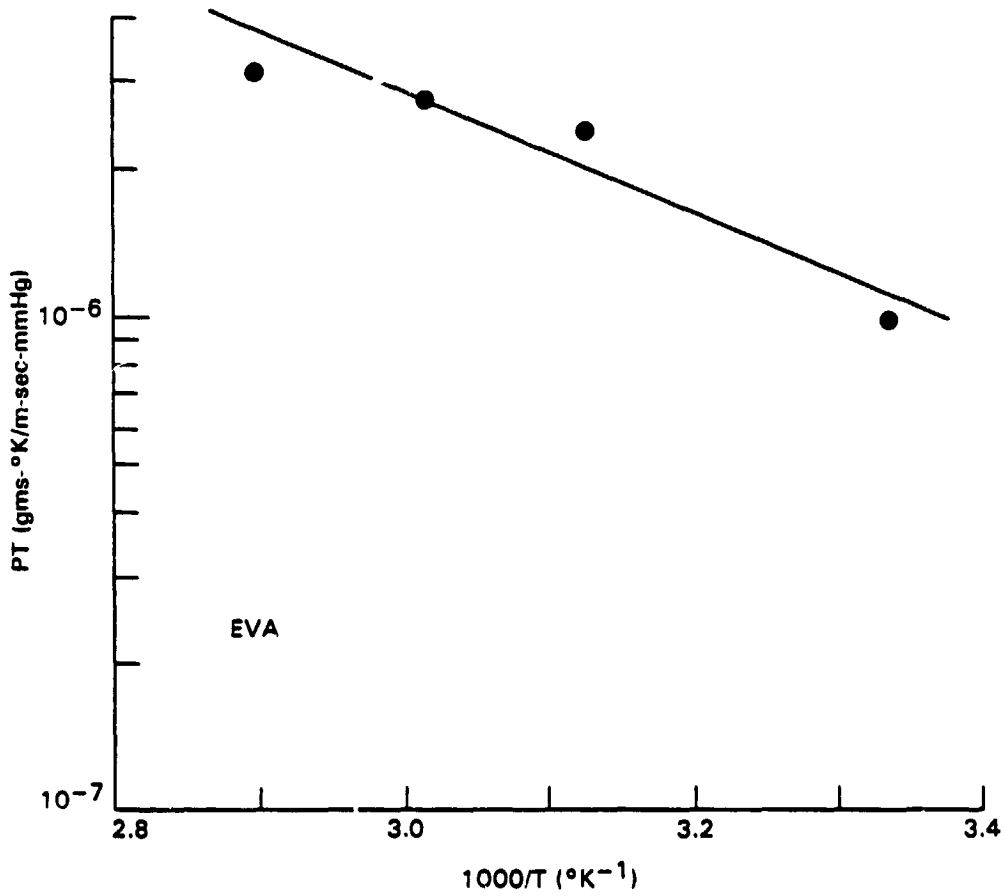
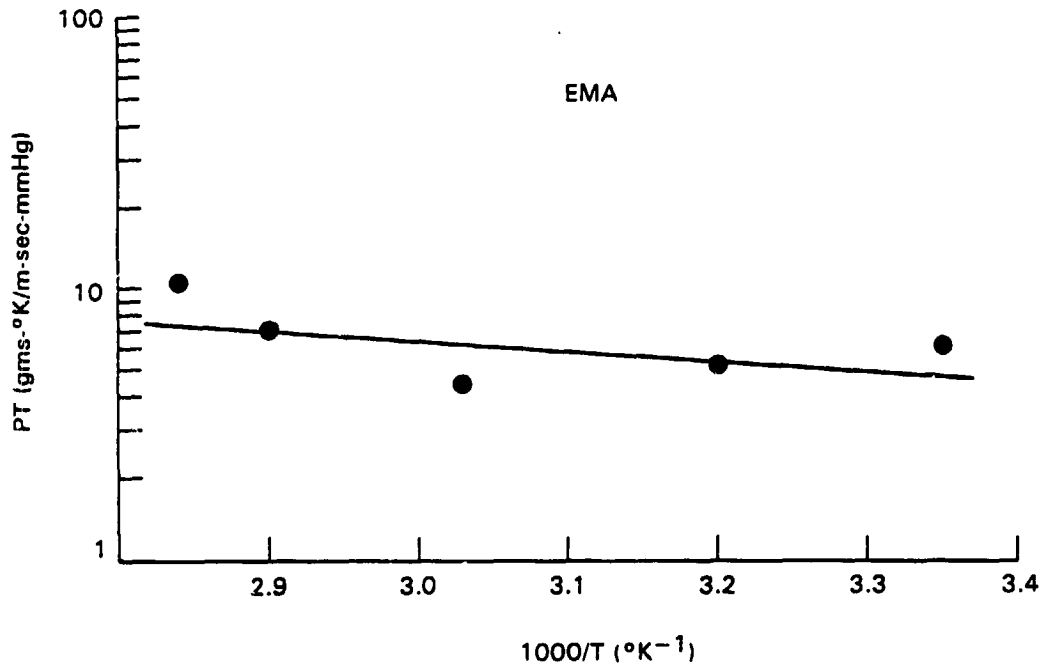
Experimental Arrangement



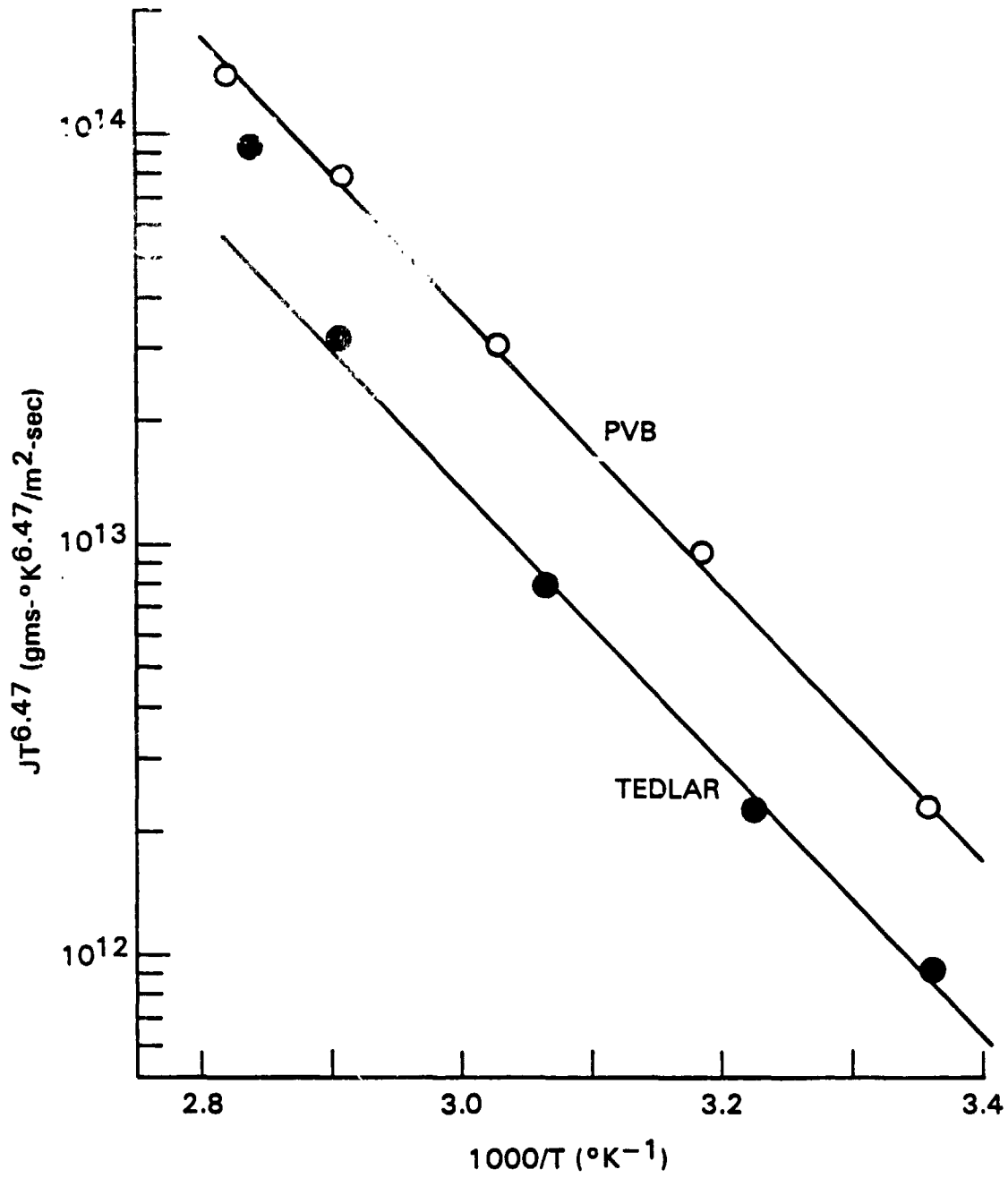
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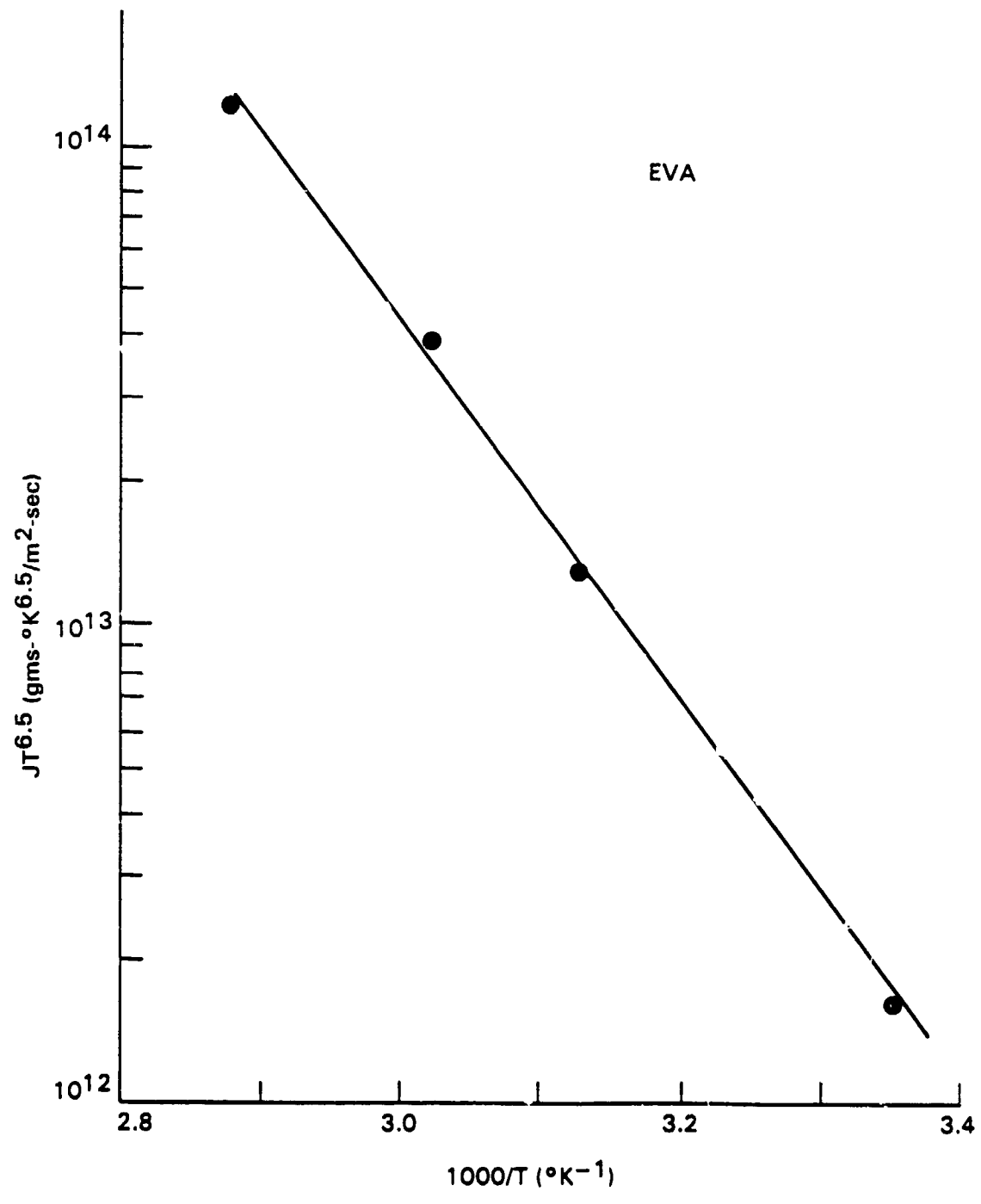
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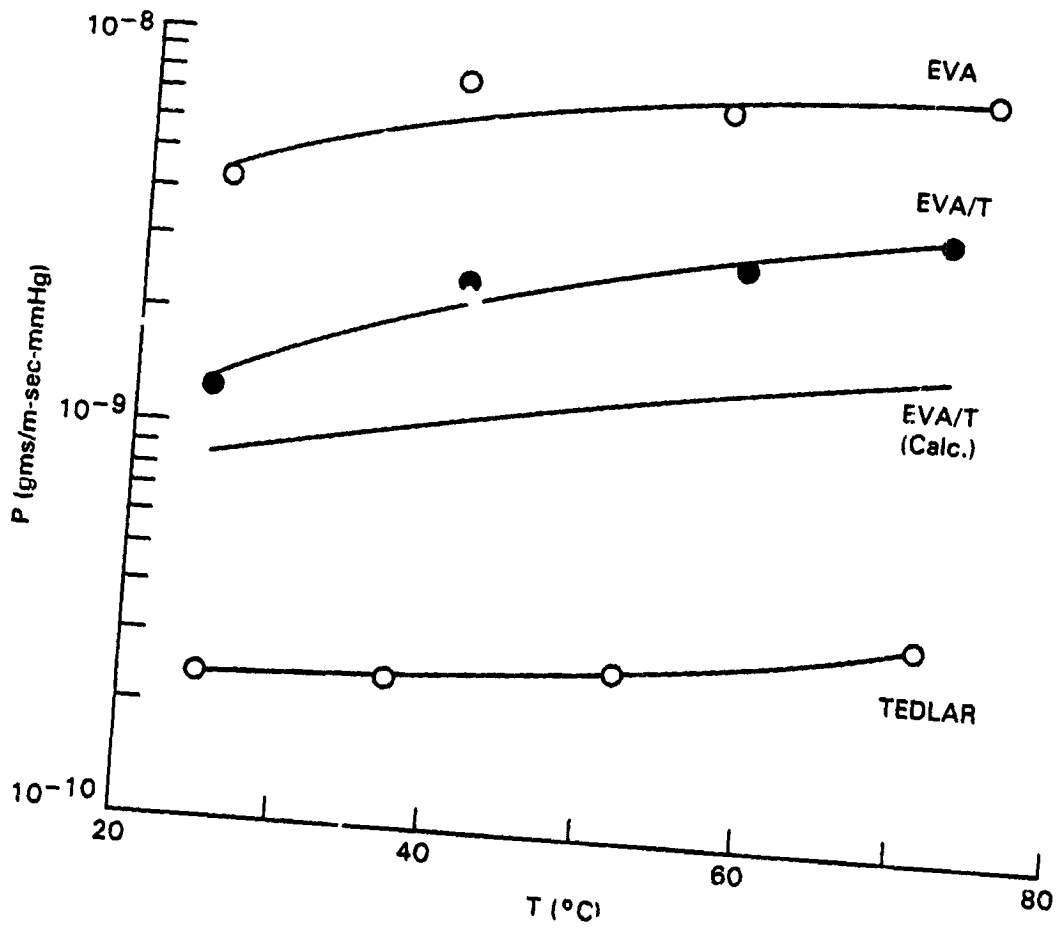
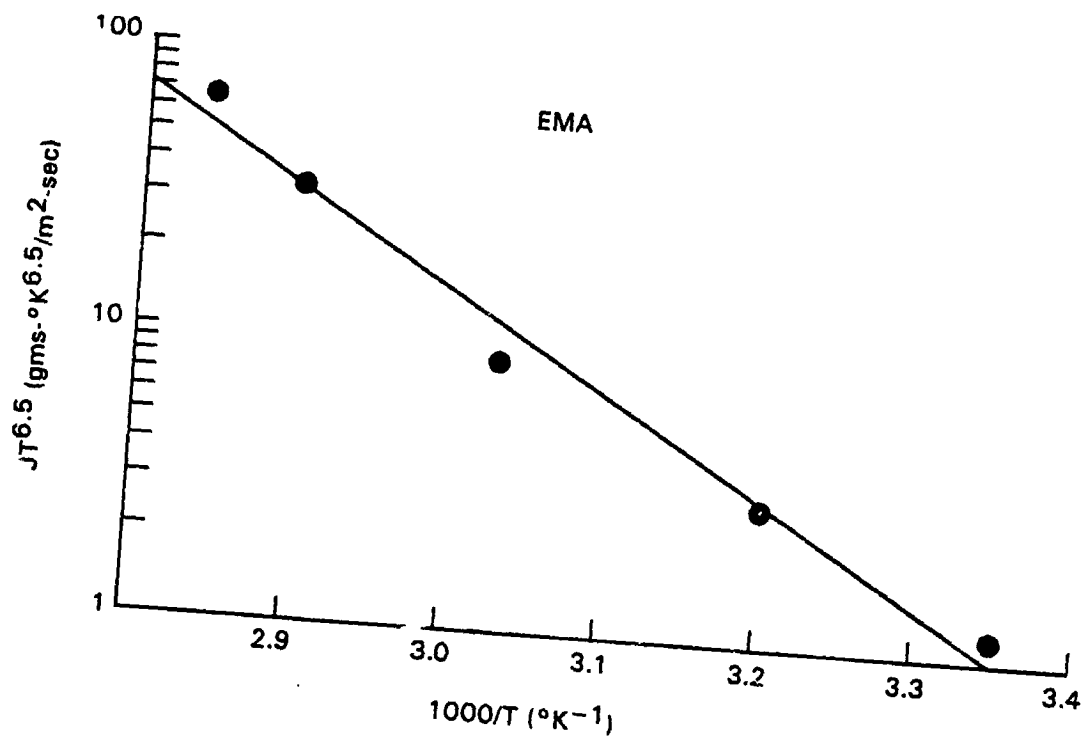
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Results

	Activation Energy (Kcal./mole)		Solubility; Parameter
	$Q_p$	$Q_J$	S
Tedlar	~ 2.9	15	.614
EMA	~ 3.1	15	5.2
PVB	~ 1.4	15	175
EVA	~ 2.8	18	730
Theoretical	4.6	14.4	—

Results

	Permeability $P \times 10^9$ (gms/m-sec-mmHg)	Thickness $d \times 10^6$ (m)	Resistance $R \times 10^5$ (m <sup>2</sup> -sec-mmHg/gm)
Tedlar	0.2	63	3.1
EMA	2.0	480	2.4
EVA	4.0	470	1.2
PVB	8.0	803	1.0

Results

Composites at 25°C

Permeability  $P \times 10^9$   
(gms/m-sec-mmHg)

	<u>Experimental</u>	<u>Calculated</u>
PVB/T	1.6	1.5
EMA/T	2.0	1.0
EVA/T	1.1	0.8

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### Conclusions

- $P_T < P_{EMA} < P_{EVA} < P_{PVB}$
- Temperature dependence of J and P for PVB, EMA, and T is consistent with evaporation-self diffusion-condensation model
- P of PVB/T composite is consistent with discrete interface model
- Water solubility: greatest in PVB, least in Tedlar

## SILICON MATERIALS

Ralph Lutwack, Chairman

The session on Silicon Materials consisted of two presentations.

JPL reviewed the FSA-sponsored Workshop on Low-Cost Polysilicon for Terrestrial Photovoltaic Solar Cell Applications which was held in Las Vegas, Nevada, October 28-30, 1985.

Union Carbide Corp. (UCC) reported on their development of fluidized-bed reactor technology for producing silicon by the pyrolysis of silane. The technical effort on this program was completed.